Si52147

## PCI-Express Gen 1, Gen 2, \& Gen 3 Nine Output Clock Generator

## Features

- PCI-Express Gen 1, Gen 2, \& Gen 3 compliant
- Low power push-pull type differential output buffers
- Integrated resistors on differentia clocks
- Output enable pin for all clocks
- Hardware selectable spread control
- Nine PCI-Express clocks
- 25 MHz crystal input or clock input
- $I^{2} \mathrm{C}$ support with readback capabilities
Triangular spread spectrum profile for maximum electromagnetic interference (EMI) reduction
- Industrial temperature: -40 to $85^{\circ} \mathrm{C}$
- 3.3 V power supply
- 48-pin QFN package


Patents pending

Si52147

## Table of Contents

Section Page

1. Electrical Specifications ..... 4
2. Functional Description ..... 7
2.1. Crystal Recommendations ..... 7
2.2. CKPWRGD_PDB (Power down) Clarification ..... 8
2.3. PDB (Power down) Assertion ..... 8
2.4. PDB Deassertion ..... 8
2.5. OE Clarification ..... 8
2.6. OE Assertion ..... 8
2.7. OE Deassertion ..... 8
2.8. SSON Clarification ..... 8
3. Test and Measurement Setup ..... 9
4. Control Registers ..... 11
4.1. Serial Data Interface ..... 11
4.2. Data Protocol ..... 11
5. Pin Descriptions: 48-Pin QFN ..... 17
6. Ordering Guide ..... 20
7. Package Outline ..... 21
Contact Information ..... 22

## Si52147

## 1. Electrical Specifications

Table 1. DC Electrical Specifications

| Parameter | Symbol | Test Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 3.3 V Operating Voltage | VDD core | $3.3 \pm 5 \%$ | 3.135 | 3.3 | 3.465 | V |
| 3.3 V Input High Voltage | $\mathrm{V}_{\mathrm{IH}}$ | Control input pins | 2.0 | - | $V_{D D}+0.3$ | V |
| 3.3 V Input Low Voltage | $\mathrm{V}_{\text {IL }}$ | Control input pins | $\mathrm{V}_{S S}-0.3$ | - | 0.8 | V |
| Input High Voltage | $\mathrm{V}_{\text {IH2C }}$ | SDATA, SCLK | 2.2 | - | - | V |
| Input Low Voltage | $\mathrm{V}_{\text {ILI2 }}$ | SDATA, SCLK | - | - | 1.0 | V |
| Input High Leakage Current | $\mathrm{I}_{\mathrm{H}}$ | Except internal pull-down resistors, $0<\mathrm{V}_{\text {IN }}<\mathrm{V}_{\mathrm{DD}}$ | - | - | 5 | $\mu \mathrm{A}$ |
| Input Low Leakage Current | IIL | Except internal pull-up resistors, $0<\mathrm{V}_{\text {IN }}<\mathrm{V}_{\mathrm{DD}}$ | -5 | - | - | $\mu \mathrm{A}$ |
| 3.3 V Output High Voltage (SE) | $\mathrm{V}_{\mathrm{OH}}$ | $\mathrm{l}_{\mathrm{OH}}=-1 \mathrm{~mA}$ | 2.4 | - | - | V |
| 3.3 V Output Low Voltage (SE) | $\mathrm{V}_{\text {OL }}$ | $\mathrm{I}_{\mathrm{OL}}=1 \mathrm{~mA}$ | - | - | 0.4 | V |
| High-impedance Output Current | $\mathrm{l}_{\mathrm{Oz}}$ |  | -10 | - | 10 | $\mu \mathrm{A}$ |
| Input Pin Capacitance | $\mathrm{C}_{\text {IN }}$ |  | 1.5 | - | 5 | pF |
| Output Pin Capacitance | $\mathrm{C}_{\text {OUT }}$ |  | - | - | 6 | pF |
| Pin Inductance | $\mathrm{L}_{\text {IN }}$ |  | - | - | 7 | nH |
| Power Down Current | $\mathrm{I}_{\text {DD_PD }}$ |  | - | - | 1 | mA |
| Dynamic Supply Current | l $\mathrm{DD}_{\text {_3.3V }}$ | All outputs enabled. Differential clocks with 5" traces and 2 pF load. | - | - | 85 | mA |

Table 2. AC Electrical Specifications

| Parameter | Symbol | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Crystal |  |  |  |  |  |  |
| Long-term Accuracy | $\mathrm{L}_{\text {ACC }}$ | Measured at $\mathrm{V}_{\mathrm{DD}} / 2$ differential | - | - | 250 | ppm |
| Clock Input |  |  |  |  |  |  |
| CLKIN Duty Cycle | $\mathrm{T}_{\mathrm{DC}}$ | Measured at $\mathrm{V}_{\mathrm{DD}} / 2$ | 47 | - | 53 | \% |
| CLKIN Rise and Fall Times | $\mathrm{T}_{\mathrm{R}} / \mathrm{T}_{\mathrm{F}}$ | Measured between $0.2 \mathrm{~V}_{\mathrm{DD}}$ and $0.8 \mathrm{~V}_{\mathrm{DD}}$ | 0.5 | - | 4.0 | V/ns |
| CLKIN Cycle to Cycle Jitter | $\mathrm{T}_{\text {CCJ }}$ | Measured at VDD/2 | - | - | 250 | ps |
| CLKIN Long Term Jitter | TLTJ | Measured at VDD/2 | - | - | 350 | ps |
| Input High Voltage | $\mathrm{V}_{\mathrm{IH}}$ | XIN/CLKIN pin | 2 | - | VDD+0.3 | V |
| Input Low Voltage | $\mathrm{V}_{\mathrm{IL}}$ | XIN/CLKIN pin | - | - | 0.8 | V |
| Input High Current | $\mathrm{IIH}^{\text {H }}$ | XIN/CLKIN pin, VIN = VDD | - | - | 35 | uA |
| Input Low Current | IIL | XIN/CLKIN pin, 0 < VIN <0.8 | -35 | - | - | uA |
| DIFF at 0.7 V |  |  |  |  |  |  |
| DIFF Duty Cycle | T ${ }_{\text {D }}$ | Measured at 0 V differential | 45 | - | 55 | \% |
| Any DIFF Clock Skew from the Earliest Bank to the Latest Bank | $\mathrm{T}_{\text {SKEW(win }}$ dow) | Measured at 0 V differential | - | - | 50 | ps |
| DIFF Cycle to Cycle Jitter | $\mathrm{T}_{\text {CCJ }}$ | Measured at 0 V differential | - | 35 | 50 | ps |
| Output PCle Gen1 REFCLK Phase Jitter | $\mathrm{RMS}_{\text {GEN } 1}$ | $\begin{gathered} \text { Includes PLL BW } 1.5-22 \mathrm{MHz}, \\ \zeta=0.54, \mathrm{Td}=10 \mathrm{~ns}, \\ \text { Ftrk=1.5 MHz with } \mathrm{BER}=1 \mathrm{E}-12 \end{gathered}$ | 0 | 40 | 108 | ps |
| Output PCle Gen2 REFCLK Phase Jitter | $\mathrm{RMS}_{\text {GEN2 }}$ | Includes PLL BW 8-16 MHz, Jitter Peaking $=3 \mathrm{~dB}, \zeta=0.54, \mathrm{Td}=12 \mathrm{~ns}$, Low Band, $\mathrm{F}<1.5 \mathrm{MHz}$ | 0 | 2 | 3.0 | ps |
| Output PCle Gen2 REFCLK Phase Jitter | $\mathrm{RMS}_{\text {GEN2 }}$ | Includes PLL BW 8-16 MHz, Jitter Peaking $=3 \mathrm{~dB}, \zeta=0.54, \mathrm{Td}=12 \mathrm{~ns}$, High Band, 1.5 MHz < F < Nyquist | 0 | 2 | 3.1 | ps |
| Output Phase Jitter ImpactPCle Gen3 | $\mathrm{RMS}_{\text {GEN3 }}$ | Includes PLL BW 2-4 MHz, $\mathrm{CDR}=10 \mathrm{MHz}$ | 0 | 0.5 | 1.0 | ps |
| DIFF Long Term Accuracy | $\mathrm{L}_{\text {ACC }}$ | Measured at 0 V differential | - | - | 100 | ppm |
| DIFF Rising/Falling Slew Rate | $\mathrm{T}_{\mathrm{R}} / \mathrm{T}_{\mathrm{F}}$ | Measured differentially from $\pm 150 \mathrm{mV}$ | 1 | - | 8 | V/ns |
| Voltage High | $\mathrm{V}_{\text {HIGH }}$ |  | - | - | 1.15 | V |
| Voltage Low | $\mathrm{V}_{\text {LOW }}$ |  | -0.3 | - | - | V |
| Crossing Point Voltage at 0.7 V Swing | $\mathrm{V}_{\text {OX }}$ |  | 300 | - | 550 | mV |
| Enable/Disable and Setup |  |  |  |  |  |  |
| Clock Stabilization from Power-up | T Stable |  | - | - | 1.8 | ms |
| Stopclock Set-up Time | $\mathrm{T}_{\text {S }}$ |  | 10.0 | - | - | ns |

## Si52147

Table 3. Absolute Maximum Conditions

| Parameter | Symbol | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Main Supply Voltage | VDD_3.3V | Functional | - | - | 4.6 | V |
| Input Voltage | $\mathrm{V}_{\mathrm{IN}}$ | Relative to $\mathrm{V}_{\text {SS }}$ | -0.5 | - | 4.6 | $\mathrm{V}_{\mathrm{DC}}$ |
| Temperature, Storage | $\mathrm{T}_{\mathrm{S}}$ | Non-functional | -65 | - | 150 | ${ }^{\circ} \mathrm{C}$ |
| Temperature, Operating Ambient | $\mathrm{T}_{\text {A }}$ | Functional | -40 | - | 85 | ${ }^{\circ} \mathrm{C}$ |
| Temperature, Junction | $\mathrm{T}_{J}$ | Functional | - | - | 150 | ${ }^{\circ} \mathrm{C}$ |
| Dissipation, Junction to Case | $\varnothing_{J C}$ | JEDEC (JESD 51) | - | - | 22 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Dissipation, Junction to Ambient | $\varnothing_{J A}$ | JEDEC (JESD 51) | - | - | 30 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| ESD Protection (Human Body Model) | ESD ${ }_{\text {HBM }}$ | JEDEC (JESD 22-A114) | 2000 | - | - | V |
| Flammability Rating | UL-94 | UL (Class) |  | V-0 |  |  |
| Moisture Sensitivity Level | MSL | JEDEC (J-STD-020) |  | 2 |  |  |
| Note: While using multiple power supplies, the voltage on any input or I/O pin cannot exceed the power pin during power-up. Power supply sequencing is not required. |  |  |  |  |  |  |

## 2. Functional Description

### 2.1. Crystal Recommendations

The clock device requires a parallel resonance crystal. Substituting a series resonance crystal causes the clock device to operate at the wrong frequency and violates the ppm specification. For most applications there is a 300 ppm frequency shift between series and parallel crystals due to incorrect loading.

Table 4. Crystal Recommendations

| Frequency <br> (Fund) | Cut | Loading | Load Cap | Shunt <br> Cap (max) | Motional <br> $(\boldsymbol{m a x})$ | Tolerance <br> $(\boldsymbol{m a x})$ | Stability <br> $(\boldsymbol{m a x})$ | Aging <br> $(\boldsymbol{m a x})$ |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 25 MHz | AT | Parallel | $12-15 \mathrm{pF}$ | 5 pF | 0.016 pF | 35 ppm | 30 ppm | 5 ppm |

### 2.1.1. Crystal Loading

Crystal loading plays a critical role in achieving low ppm performance. To realize low ppm performance, use the total capacitance the crystal sees to calculate the appropriate capacitive loading (CL).
Figure 1 shows a typical crystal configuration using the two trim capacitors. It is important that the trim capacitors are in series with the crystal. It is not true that load capacitors are in parallel with the crystal and are approximately equal to the load capacitance of the crystal.


Figure 1. Crystal Capacitive Clarification

### 2.1.2. Calculating Load Capacitors

In addition to the standard external trim capacitors, consider the trace capacitance and pin capacitance to calculate the crystal loading correctly. Again, the capacitance on each side is in series with the crystal. The total capacitance on both side is twice the specified crystal load capacitance (CL). Trim capacitors are calculated to provide equal capacitive loading on both sides.


Figure 2. Crystal Loading Example

Use the following formulas to calculate the trim capacitor values for Ce 1 and Ce 2 .

## Load Capacitance (each side)

$$
C e=2 \times C L-(C s+C i)
$$

Total Capacitance (as seen by the crystal)
CLe $=\frac{1}{\left(\frac{1}{C e 1+C s 1+C i 1}+\frac{1}{C e 2+C s 2+C i 2}\right)}$

- CL: Crystal load capacitance
- CLe: Actual loading seen by crystal using standard value trim capacitors
- Ce: External trim capacitors
- Cs: Stray capacitance (terraced)
- Ci : Internal capacitance (lead frame, bond wires, etc.)


### 2.2. CKPWRGD_PDB (Power down) Clarification

The CKPWRGD_PDB pin is a dual-function pin. During initial power up, the pin functions as CKPWRGD. Upon the first powerup if the CKPWRGD is low, the device outputs will be disabled, but the crystal oscillator and $\mathrm{I}^{2} \mathrm{C}$ logics are active. Once CKPWRGD has been sampled high by the clock chip, the pin assumes a PDB functionality. When the pin has assumed a PDB functionality and the pin is pull low, the device will be placed in standby mode.

### 2.3. PDB (Power down) Assertion

The PDB pin is an asynchronous active low input used to disable all clocks in a glitch free manner. All outputs will be driven low in power down mode. In power down mode, all outputs, the crystal oscillator and the $I^{2} \mathrm{C}$ logic are disabled.

### 2.4. PDB Deassertion

When a valid rising edge on CKPWRGD/PDB pin is applied, all outputs are enabled in a glitch free manner within two to six output clock cycle.

### 2.5. OE Clarification

The OE pins are active high inputs used to enable and disable the output clocks. To enable the output clock, the OE pin needs to be logic high and the $I^{2} \mathrm{C}$ output enable bit needs to be logic high. There are two methods to disable the output clocks: the OE is pulled to a logic low, or the $I^{2} \mathrm{C}$ enable bit is set to a logic low. The OE pins is required to be driven at all time and even though it has an internally $100 \mathrm{k} \Omega$ resistor.

### 2.6. OE Assertion

The OE signals are active high input used for synchronous stopping and starting the DIFF output clocks respectively while the rest of the clock generator continues to function. The assertion of the OE signal by making it logic high causes stopped respective DIFF output to resume normal operation. No short or stretched clock pulses are produced when the clock resumes. The maximum latency from the assertion to active outputs is no more than two to six output clock cycles.

### 2.7. OE Deassertion

When the OE pin is deasserted by making its logic low, the corresponding DIFF output is stopped cleanly, and the final output state is driven low.

### 2.8. SSON Clarification

SSON is an active input used to enable $-0.5 \%$ spread on all DIFF outputs. When sampled high, $-0.5 \%$ spread is enabled on all DIFF outputs. When sampled low, the DIFF output frequencies are non-spread.

## 3. Test and Measurement Setup

This diagram shows the test load configuration for the differential clock signals.


Figure 3. 0.7 V Differential Load Configuration


Figure 4. Differential Output Signals (for AC Parameters Measurement)


Figure 5. Single-ended Measurement for Differential Output Signals (for AC Parameters Measurement)

## 4. Control Registers

### 4.1. Serial Data Interface

To enhance the flexibility and function of the clock synthesizer, a two-signal serial interface is provided. Through the Serial Data Interface, various device functions, such as individual clock output buffers are individually enabled or disabled. The registers associated with the Serial Data Interface initialize to their default setting at power-up. The use of this interface is optional. Clock device register changes are normally made at system initialization, if any are required. The interface cannot be used during system operation for power management functions.

### 4.2. Data Protocol

The clock driver serial protocol accepts byte write, byte read, block write, and block read operations from the controller. For block write/read operation, access the bytes in sequential order from lowest to highest (most significant bit first) with the ability to stop after any complete byte is transferred. For byte write and byte read operations, the system controller can access individually indexed bytes. The offset of the indexed byte is encoded in the command code described in Table 1 on page 4.
The block write and block read protocol is outlined in Table 5 while Table 6 outlines byte write and byte read protocol. The slave receiver address is 11010110 (D6h).

Table 5. Block Read and Block Write Protocol

| Block Write Protocol |  | Block Read Protocol |  |
| :---: | :--- | :---: | :--- |
| Bit | Description | Bit | Description |
| 1 | Start | 1 | Start |
| $8: 2$ | Slave address-7 bits | $8: 2$ | Slave address-7 bits |
| 9 | Write | 9 | Write |
| 10 | Acknowledge from slave | 10 | Acknowledge from slave |
| $18: 11$ | Command Code-8 bits | $18: 11$ | Command Code-8 bits |
| 19 | Acknowledge from slave | 20 | Rcknowledge from slave |
| $27: 20$ | Byte Count-8 bits | $27: 21$ | Slave address-7 bits |
| 28 | Acknowledge from slave | 28 | Read = 1 |
| $36: 29$ | Data byte 1-8 bits | 29 | Acknowledge from slave |
| 37 | Acknowledge from slave | $37: 30$ | Byte Count from slave-8 bits |
| $45: 38$ | Data byte 2-8 bits | 38 | Acknowledge |
| 46 | Acknowledge from slave | $46: 39$ | Data byte 1 from slave-8 bits |
| $\ldots$. | Data Byte/Slave Acknowledges | 47 | Acknowledge |
| $\ldots$. | Data Byte N-8 bits | $55: 48$ | Data byte 2 from slave-8 bits |
| $\ldots$. | Acknowledge from slave | 56 | Acknowledge |
| $\ldots$. | Stop | $\ldots$. | Data bytes from slave/Acknowledge |
|  |  | $\ldots .$. | Data Byte N from slave-8 bits |
|  |  | $\ldots .$. | NOT Acknowledge |
|  |  | $\ldots$. | Stop |
|  |  |  |  |

## Si52147

Table 6. Byte Read and Byte Write Protocol

| Byte Write Protocol |  | Byte Read Protocol |  |
| :---: | :--- | :---: | :--- |
| Bit | Description | Bit | Description |
| 1 | Start | 1 | Start |
| $8: 2$ | Slave address-7 bits | $8: 2$ | Slave address-7 bits |
| 9 | Write | 9 | Write |
| 10 | Acknowledge from slave | 10 | Acknowledge from slave |
| $18: 11$ | Command Code-8 bits | $18: 11$ | Command Code-8 bits |
| 19 | Acknowledge from slave | 19 | Acknowledge from slave |
| $27: 20$ | Data byte-8 bits | 20 | Repeated start |
| 28 | Acknowledge from slave | $27: 21$ | Slave address-7 bits |
| 29 | Stop | 28 | Read |
|  |  | 29 | Acknowledge from slave |
|  |  | $37: 30$ | Data from slave-8 bits |
|  |  | 38 | NOT Acknowledge |
|  |  | 39 | Stop |

## Control Register 0. Byte 0

| Bit | D7 | D6 | D5 | D4 | D3 | D2 | D1 | D0 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Name |  |  |  |  |  |  |  |  |
| Type | R/W | R/W | R/W | R/W | R/W | R/W | R/W | R/W |

Reset settings $=00000000$

| Bit | Name | Function |
| :---: | :---: | :---: |
| $7: 0$ | Reserved |  |

## Control Register 1. Byte 1

| Bit | D7 | D6 | D5 | D4 | D3 | D2 | D1 | D0 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Name |  |  |  | DIFF0_OE |  | DIFF1_OE | DIFF2_OE | DIFF3_OE |
| Type | R/W | R/W | R/W | R/W | R/W | R/W | R/W | R/W |

Reset settings = 00010111

| Bit | Name | Function |
| :---: | :---: | :--- | :--- |
| $7: 5$ | Reserved |  |
| 4 | DIFF0_OE | Output Enable for DIFF0. <br> 0: Output disabled. <br> 1: Output enabled. |
| 3 | Reserved |  |
| 2 | DIFF1_OE | Output Enable for DIFF1. <br> 0: Output disabled. <br> 1: Output enabled. |
| 1 | DIFF2_OE | Output Enable for DIFF2. <br> 0: Output disabled. <br> 1: Output enabled. |
| 0 | DIFF3_OE | Output Enable for DIFF3. <br> 0: Output disabled. <br> 1: Output enabled. |

## Control Register 2. Byte 2

| Bit | D7 | D6 | D5 | D4 | D3 | D2 | D1 | D0 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Name | DIFF4_OE | DIFF5_OE | DIFF6_OE | DIFF7_OE | DIFF8_OE |  |  |  |
| Type | R/W | R/W | R/W | R/W | R/W | R/W | R/W | R/W |

Reset settings $=11111000$

| Bit | Name | Function |
| :---: | :---: | :--- |
| 7 | DIFF4_OE | Output Enable for DIFF4. <br> 0: Output disabled. <br> 1: Output enabled. |
| 6 | DIFF5_OE | Output Enable for DIFF5. <br> 0: Output disabled. <br> 1: Output enabled. |
| 5 | DIFF6_OE | Output Enable for DIFF6. <br> 0: Output disabled. <br> 1: Output enabled. |
| 4 | DIFF7_OE | Output Enable for DIFF7. <br> 0: Output disabled. <br> 1: Output enabled. |
| 3 | DIFF8_OE | Output Enable for DIFF8. <br> 0: Output disabled. <br> 1: Output enabled. |
| $2: 0$ | Reserved |  |

## Control Register 3. Byte 3

| Bit | D7 | D6 | D5 | D4 | D3 | D2 | D1 | D0 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Name | Rev Code[3:0] |  |  |  |  |  |  | Vendor ID[3:0] |
| Type | R/W | R/W | R/W | R/W | R/W | R/W | R/W | R/W |

Reset settings $=00001000$

| Bit | Name | Function |  |
| :---: | :---: | :--- | :--- |
| $7: 4$ | Rev Code[3:0] | Program Revision Code. |  |
| $3: 0$ | Vendor ID[3:0] | Vendor Identification Code. |  |

## Control Register 4. Byte 4

| Bit | D7 | D6 | D5 | D4 | D3 | D2 | D1 | D0 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Name | BC[7:0] |  |  |  |  |  |  |  |
| Type | R/W | R/W | R/W | R/W | R/W | R/W | R/W | R/W |

Reset settings $=00000110$

| Bit | Name |  | Function |
| :---: | :---: | :--- | :--- |
| $7: 0$ | $B C[7: 0]$ | Byte Count Register. |  |

Control Register 5. Byte 5

| Bit | D7 | D6 | D5 | D4 | D3 | D2 | D1 | D0 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Name | DIFF_Amp_Sel | DIFF_Amp_CntI[2] | DIFF_Amp_Cnt[[1] | DIFF_Amp_Cnt[[0] |  |  |  |  |
| Type | R/W | R/W | R/W | R/W | R/W | R/W | R/W | R/W |

Reset settings = 11011000

| Bit | Name | Function |
| :---: | :---: | :--- |
| 7 | DIFF_Amp_Sel | Amplitude Control for DIFF Differential Outputs. <br> 0: Differential outputs with Default amplitude. <br> 1: Differential outputs amplitude is set by Byte 5[6:4]. |
| 6 | DIFF_Amp_CntI[2] | DIFF Differential Outputs Amplitude Adjustment. |
| 5 | DIFF_Amp_CntI[1] | 000: 300 mV 001: 400 mV 010: $500 \mathrm{mV} \quad 011: 600 \mathrm{mV}$ |
| 4 | DIFF_Amp_CntI[0] | 100: 700 mV 101: 800 mV 110: $900 \mathrm{mV} \quad 111: 1000 \mathrm{mV}$ |
| $3: 0$ | Reserved |  |

## 5. Pin Descriptions: 48-Pin QFN



Notes:

1. Internal 100 kohm pull-up.
2. Internal 100 kohm pull-down.

Table 7. Part Number 48-Pin QFN Descriptions

| Pin \# | Name | Type | Description |
| :---: | :---: | :---: | :--- |
| 1 | VDD | PWR | 3.3 V Power Supply |
| 2 | VDD | PWR | 3.3 V Power Supply |
| 3 | OE0 | I,PU | 3.3 V input to disable DIFFO (internal $100 \mathrm{k} \Omega$ pull-up). <br> Refer to Table 1 on page 4 for OE specifications. |
| 4 | OE1 | I,PU | 3.3 V input to disable DIFF1 (internal $100 \mathrm{k} \Omega$ pull-up). <br> Refer to Table 1 on page 4 for OE specifications. |
| 5 | SSON | I, PD | 3.3 V-tolerant input for enabling -0.5\% spread on DIFF clocks (internal <br> 100 k $\Omega$ pull-down) |
| 6 | VSS | GND | Ground |

Table 7. Part Number 48-Pin QFN Descriptions

| Pin \# | Name | Type | Description |
| :---: | :---: | :---: | :---: |
| 7 | VSS | GND | Ground |
| 8 | OE2 | I,PU | 3.3 V input to disable DIFF2 (internal $100 \mathrm{k} \Omega$ pull-up). Refer to Table 1 on page 4 for OE specifications. |
| 9 | OE3 | I,PU | 3.3 V input to disable DIFF3 (internal $100 \mathrm{k} \Omega$ pull-up). Refer to Table 1 on page 4 for OE specifications. |
| 10 | OE[4:5] | I,PU | 3.3 V input to disable DIFF[4:5] (internal $100 \mathrm{k} \Omega$ pull-up). Refer to Table 1 on page 4 for OE specifications. |
| 11 | OE[6:8] | I,PU | 3.3 V input to disable DIFF[6:8] (internal $100 \mathrm{k} \Omega$ pull-up). Refer to Table 1 on page 4 for OE specifications. |
| 12 | VDD | PWR | 3.3 V Power Supply |
| 13 | VDD | PWR | 3.3V Power Supply |
| 14 | DIFF0 | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 15 | $\overline{\text { DIFF0 }}$ | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 16 | VSS | VSS | Ground |
| 17 | DIFF1 | O, DIF | 0.7 V, 100 MHz differential clock |
| 18 | $\overline{\text { DIFF1 }}$ | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 19 | DIFF2 | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 20 | $\overline{\text { DIFF2 }}$ | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 21 | DIFF3 | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 22 | $\overline{\text { DIFF3 }}$ | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 23 | VDD | PWR | 3.3V Power Supply |
| 24 | VSS | GND | Ground |
| 25 | $\overline{\text { DIFF4 }}$ | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 26 | DIFF4 | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 27 | $\overline{\text { DIFF5 }}$ | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 28 | DIFF5 | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 29 | VSS | GND | Ground |
| 30 | $\overline{\text { DIFF6 }}$ | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 31 | DIFF6 | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 32 | $\overline{\text { DIFF7 }}$ | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 33 | DIFF7 | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |

Table 7. Part Number 48-Pin QFN Descriptions

| Pin \# | Name | Type | Description |
| :---: | :---: | :---: | :--- |
| 34 | VDD | PWR | 3.3 V Power Supply |
| 35 | $\overline{\text { DIFF8 }}$ | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 36 | DIFF8 | O, DIF | $0.7 \mathrm{~V}, 100 \mathrm{MHz}$ differential clock |
| 37 | SCLK | I | SMBus compatible SCLOCK |
| 38 | SDATA | I/O | SMBus compatible SDATA |
| 39 | CKPWRGD_PDB | I, PU | 3.3 V CMOS input. A real-time active low input for asserting power <br> down (PDB) and disabling all outputs (internal 100 k $\Omega$ pull-up). |
| 40 | VDD_CORE | PWR | 3.3 V Power Supply |
| 41 | XOUT | O | 25.00 MHz Crystal output, Float XOUT if using only CLKIN (Clock input) |
| 42 | XIN/CLKIN | I | 25.00 MHz Crystal input or 3.3 V, 25 MHz Clock Input |
| 43 | NC | NC | No Connect |
| 44 | NC | NC | No Connect |
| 45 | VSS_CORE | GND | Ground |
| 46 | VSS | GND | Ground |
| 47 | NC | NC | No Connect |
| 48 | NC | NC | No Connect |
| 49 | GND | GND | Ground for bottom pad of the IC. |

## Si52147

6. Ordering Guide

| Part Number | Package Type | Temperature |
| :---: | :---: | :---: |
| Lead-free |  |  |
| Si52147-A01AGM | 48-pin QFN | Industrial, -40 to $85^{\circ} \mathrm{C}$ |
| Si52147-A01AGMR | 48-pin QFN-Tape and Reel | Industrial, -40 to $85^{\circ} \mathrm{C}$ |

## 7. Package Outline

Figure 6 illustrates the package details for the Si52147. Table 8 lists the values for the dimensions shown in the illustration.


Figure 6. 48-Pin Quad Flat No Lead (QFN) Package

## Table 8. Package Diagram Dimensions

| Symbol | Millimeters |  |  |
| :---: | :---: | :---: | :---: |
|  | Min | Nom | Max |
| A | 0.70 | 0.75 | 0.80 |
| A1 | 0.00 | 0.025 | 0.05 |
| b | 0.15 | 0.20 | 0.25 |
| D | 6.00 BSC |  |  |
| D2 | 4.30 | 4.40 | 4.50 |
| e | 0.40 BSC |  |  |
| E | 6.00 BSC |  |  |
| E2 | 4.30 | 4.40 | 4.50 |
| L | 0.30 | 0.40 | 0.50 |
| aaa | 0.10 |  |  |
| bbb | 0.10 |  |  |
| ccc | 0.08 |  |  |
| ddd | 0.07 |  |  |
| Notes: <br> 1. All dimensions shown are in millimeters (mm) unless otherwise noted. <br> 2. Dimensioning and Tolerancing per ANSI Y14.5M-1994. <br> 3. This drawing conforms to JEDEC outline MO-220, variation VGGD-8 <br> 4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components |  |  |  |
|  |  |  |  |

## CONTACT InFORMATION

## Silicon Laboratories Inc.

400 West Cesar Chavez

Austin, TX 78701
Tel: 1+(512) 416-8500
Fax: 1+(512) 416-9669
Toll Free: 1+(877) 444-3032
Please visit the Silicon Labs Technical Support web page:
https://www.silabs.com/support/pages/contacttechnicalsupport.aspx
and register to submit a technical support request.

The information in this document is believed to be accurate in all respects at the time of publication but is subject to change without notice. Silicon Laboratories assumes no responsibility for errors and omissions, and disclaims responsibility for any consequences resulting from the use of information included herein. Additionally, Silicon Laboratories assumes no responsibility for the functioning of undescribed features or parameters. Silicon Laboratories reserves the right to make changes without further notice. Silicon Laboratories makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does Silicon Laboratories assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation consequential or incidental damages. Silicon Laboratories products are not designed, intended, or authorized for use in applications intended to support or sustain life, or for any other application in which the failure of the Silicon Laboratories product could create a situation where personal injury or death may occur. Should Buyer purchase or use Silicon Laboratories products for any such unintended or unauthorized application, Buyer shall indemnify and hold Silicon Laboratories harmless against all claims and damages.

Silicon Laboratories and Silicon Labs are trademarks of Silicon Laboratories Inc.
Other products or brandnames mentioned herein are trademarks or registered trademarks of their respective holders.

